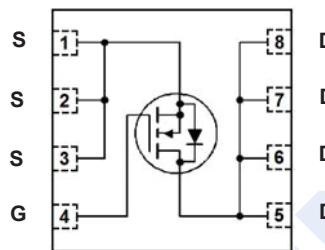


N-Channel MOSFET

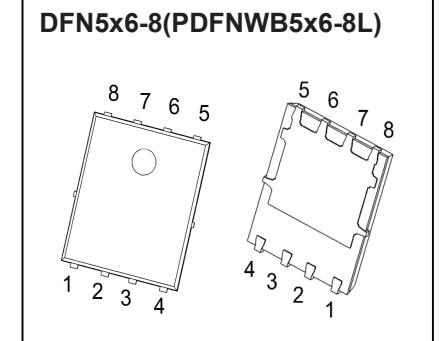
AON6516 (KON6516)

■ Features

- V_{DS} (V) = 30 V
- $I_{D\text{MAX}}$ (at V_{GS} = 10 V) = 32 A
- $R_{DS(\text{ON})}$ (at V_{GS} = 10 V) < 5 mΩ
- $R_{DS(\text{ON})}$ (at V_{GS} = 4.5 V) < 8 mΩ
- Low Gate Charge
- High Current Capability



DFN5x6-8(PDFNWB5x6-8L)

■ Absolute Maximum Ratings (T_A = 25°C unless otherwise noted)

Parameter		Symbol	Rating	Unit
Drain-Source Voltage		V_{DS}	30	V
Gate-Source Voltage		V_{GS}	± 20	
Continuous Drain Current ^G	$T_c=25^\circ\text{C}$	I_D	32	A
	$T_c=100^\circ\text{C}$		25	
Pulsed Drain Current ^C		I_{DM}	127	
Continuous Drain Current	$T_A=25^\circ\text{C}$	I_{DSM}	27	
	$T_A=70^\circ\text{C}$		22	
Avalanche Current ^C		I_{AS}	34	
Avalanche Energy $L = 0.05 \text{ mH}^{\text{C}}$		E_{AS}	29	mJ
V_{DS} Spike	100ns	V_{SPIKE}	36	V
Power Dissipation ^B	$T_c=25^\circ\text{C}$	P_D	25	W
	$T_c=100^\circ\text{C}$		10	
Power Dissipation ^A	$T_A=25^\circ\text{C}$	P_{DSM}	6	°C/W
	$T_A=70^\circ\text{C}$		3.8	
Thermal Resistance.Junction- to-Ambient ^A	$t \leqslant 10\text{s}$	R_{thJA}	21	°C/W
Thermal Resistance.Junction- to-Ambient ^{A,D}	Steady-State		53	
Thermal Resistance.Junction- to-Case	Steady-State	R_{thJC}	5	
Junction Temperature		T_J	150	°C
Storage Temperature Range		T_{stg}	-55 to 150	

N-Channel MOSFET

AON6516 (KON6516)

■ Electrical Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	BV_{DSS}	$I_D = 250 \mu\text{A}, V_{GS} = 0\text{V}$	30			V
Zero Gate Voltage Drain Current	$I_{DS(on)}$	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$		1		μA
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55^\circ\text{C}$		5		
Gate to Source Leakage Current	I_{GS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Gate to Source Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	1.2		2.2	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$		5		$\text{m}\Omega$
		$V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}, T_J = 125^\circ\text{C}$		8		
		$V_{GS} = 4.5 \text{ V}, I_D = 20 \text{ A}$		8		
Forward Transconductance	g_{FS}	$V_{DS} = 5 \text{ V}, I_D = 20 \text{ A}$		83		S
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}, V_{DS} = 15 \text{ V}, f = 1 \text{ MHz}$		1229		pF
Output Capacitance	C_{oss}			526		
Reverse Transfer Capacitance	C_{rss}			83		
Gate Resistance	R_g	$V_{GS} = 0 \text{ V}, V_{DS} = 0 \text{ V}, f = 1 \text{ MHz}$	0.8		2.6	Ω
Total Gate Charge	$Q_{g(10V)}$	$V_{GS} = 10 \text{ V}, V_{DS} = 15 \text{ V}, I_D = 20 \text{ A}$		24	33	nC
Total Gate Charge	$Q_{g(4.5V)}$			12	17	
Gate Source Charge	Q_{gs}			4		
Gate Drain Charge	Q_{gd}			5.5		
Turn-On Delay Time	$t_{d(on)}$			7.0		ns
Turn-On Rise Time	t_r	$V_{GS} = 10 \text{ V}, V_{DS} = 15 \text{ V}, R_L = 0.75 \Omega, R_{GEN} = 3 \Omega$		4.8		
Turn-Off Delay Time	$t_{d(off)}$			24.0		
Turn-Off Fall Time	t_f			5.8		
Body Diode Reverse Recovery Time	t_{rr}	$I_F = 20 \text{ A}, dI/dt = 500 \text{ A}/\mu\text{s}$		12.6		nC
Body Diode Reverse Recovery Charge	Q_{rr}			15.2		
Maximum Body-Diode Continuous Current	I_S				30	A
Diode Forward Voltage	V_{SD}	$V_{GS} = 0 \text{ V}, I_S = 1 \text{ A}$			1	V

Notes:

- A. The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The Power dissipation P_{DSM} is based on $R_{\theta JA}$ and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design.
- B. The power dissipation P_D is based on $T_J(\text{MAX})=150^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.
- C. Single pulse width limited by junction temperature $T_J(\text{MAX})=150^\circ\text{C}$.
- D. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to case $R_{\theta JC}$ and case to ambient.
- E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.
- F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_J(\text{MAX})=150^\circ\text{C}$. The SOA curve provides a single pulse rating.
- G. The maximum current rating is package limited.
- H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$.

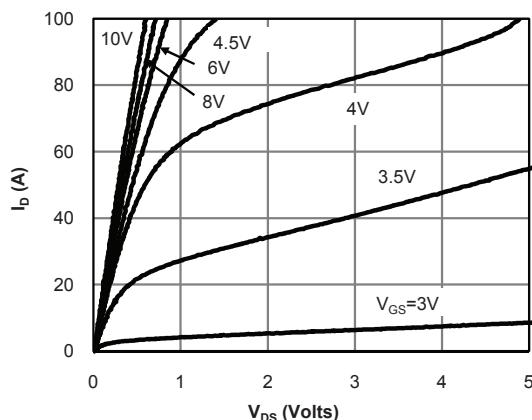
N-Channel MOSFET**AON6516 (KON6516)****■ Typical Electrical and Thermal Characteristics**

Fig 1: On-Region Characteristics (Note E)

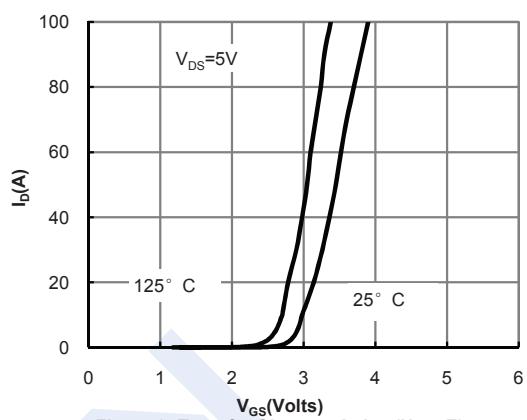


Figure 2: Transfer Characteristics (Note E)

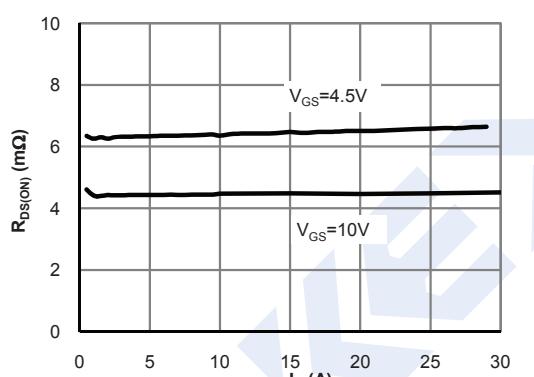


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

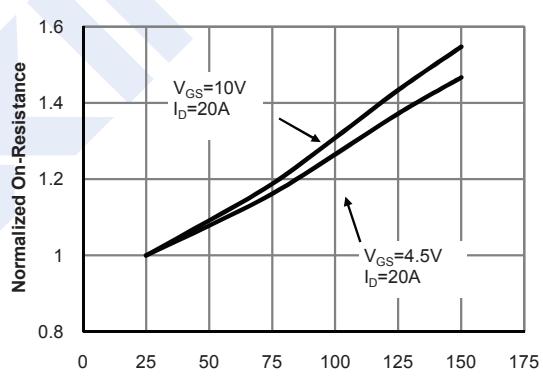


Figure 4: On-Resistance vs. Junction Temperature (Note E)

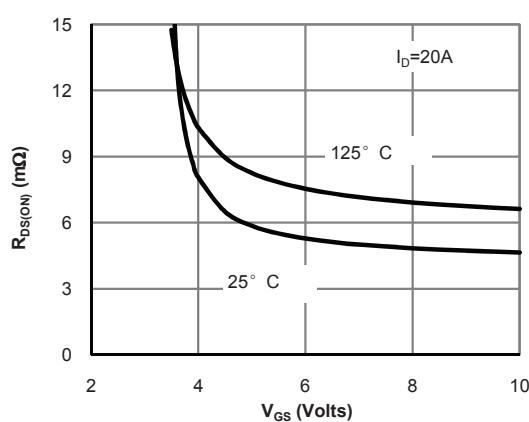


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

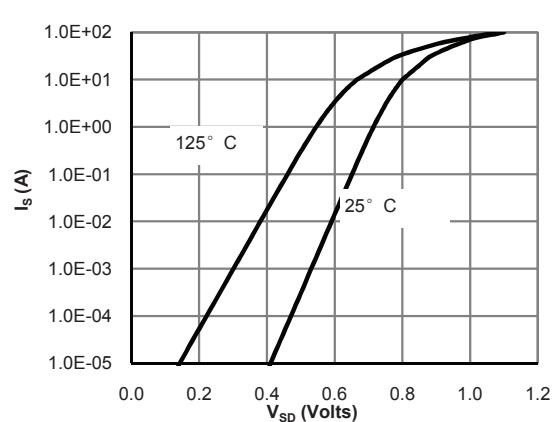


Figure 6: Body-Diode Characteristics (Note E)

N-Channel MOSFET

AON6516 (KON6516)

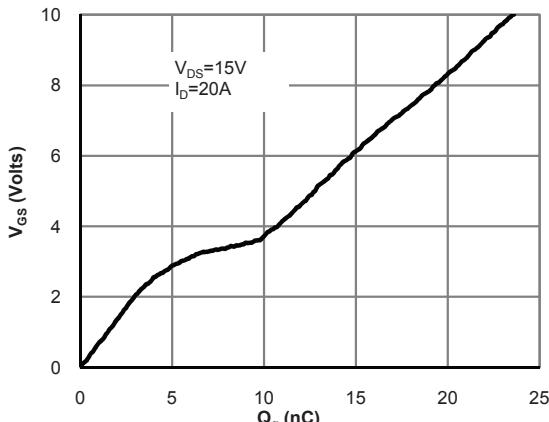


Figure 7: Gate-Charge Characteristics

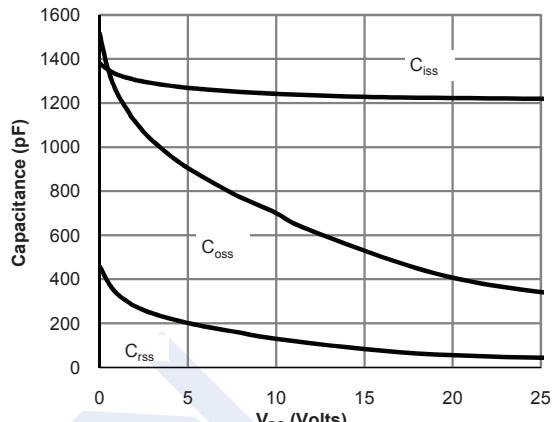


Figure 8: Capacitance Characteristics

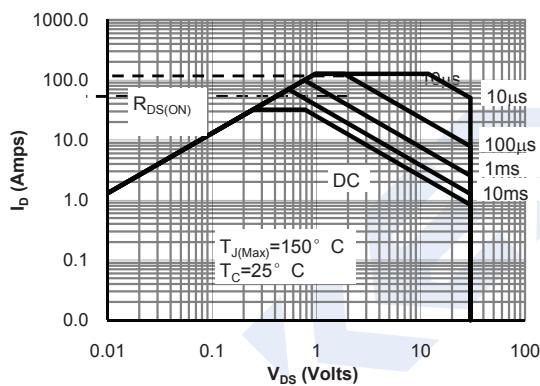


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

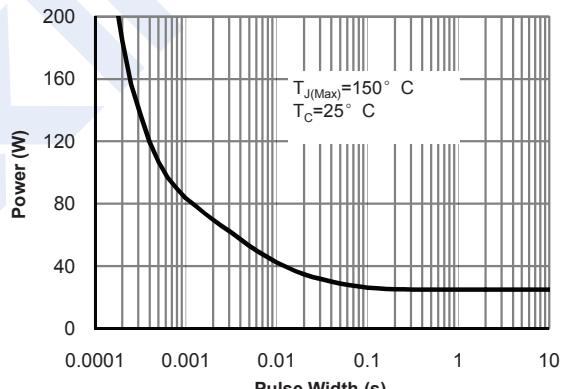


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

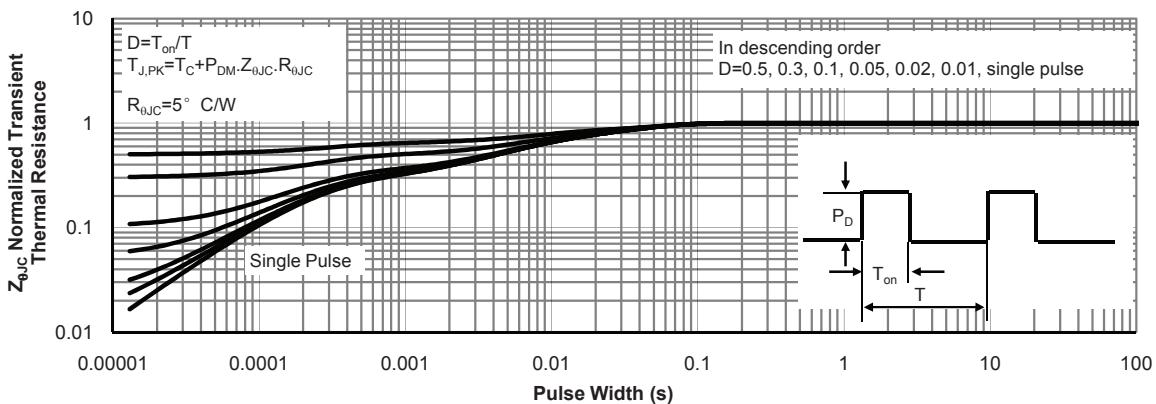


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

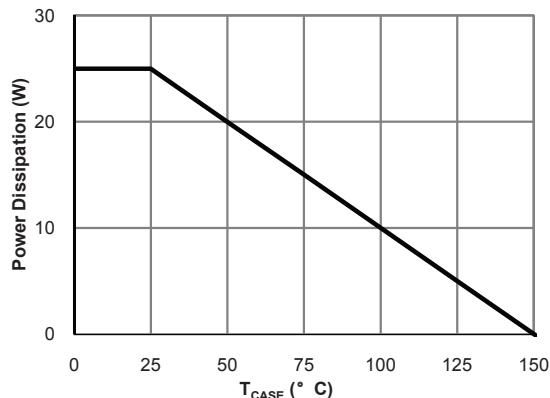
N-Channel MOSFET**AON6516 (KON6516)**

Figure 12: Power De-rating (Note F)

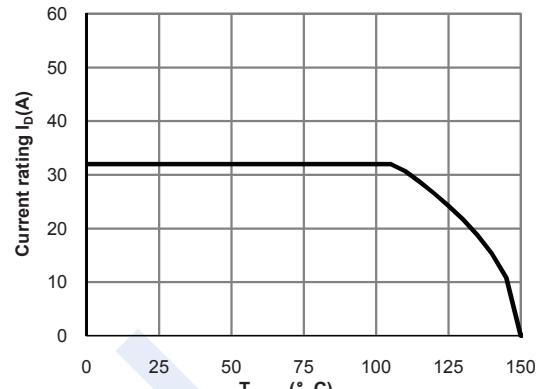


Figure 13: Current De-rating (Note F)

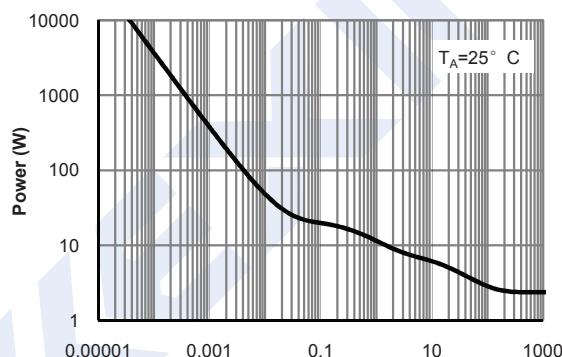


Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

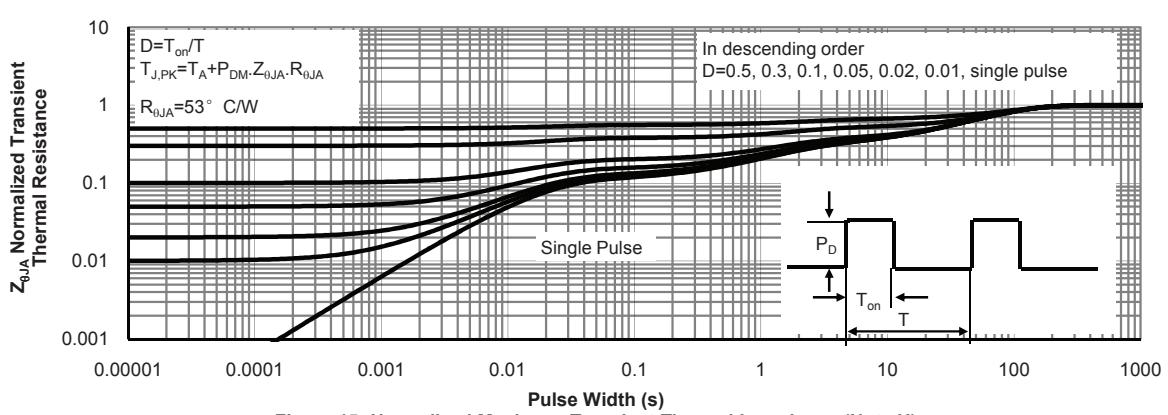
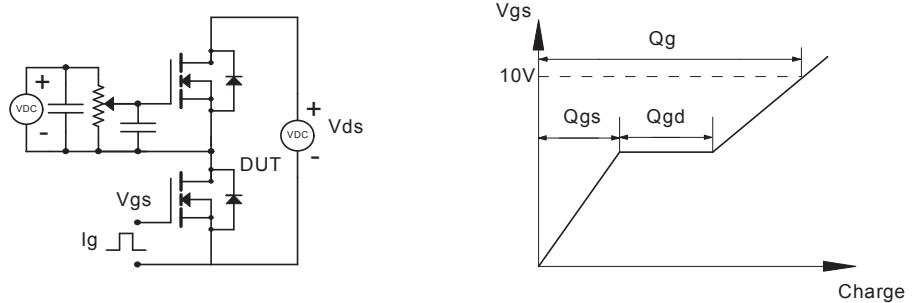


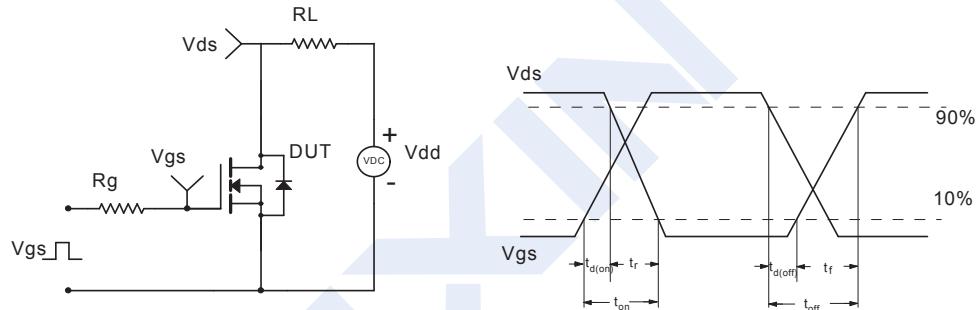
Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)

N-Channel MOSFET**AON6516 (KON6516)**

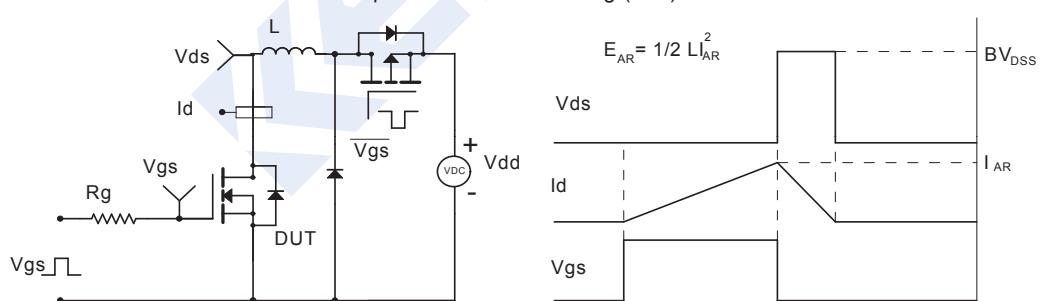
Gate Charge Test Circuit & Waveform



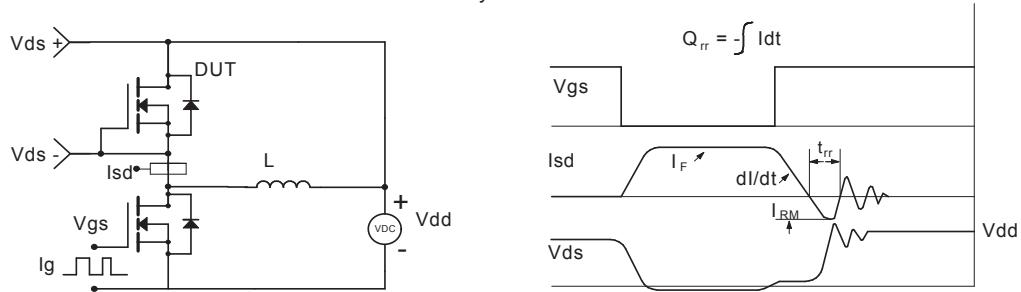
Resistive Switching Test Circuit & Waveforms

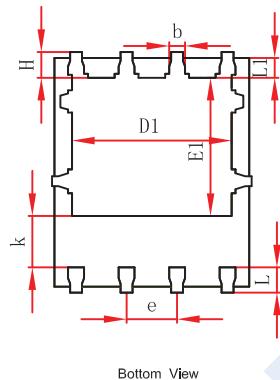
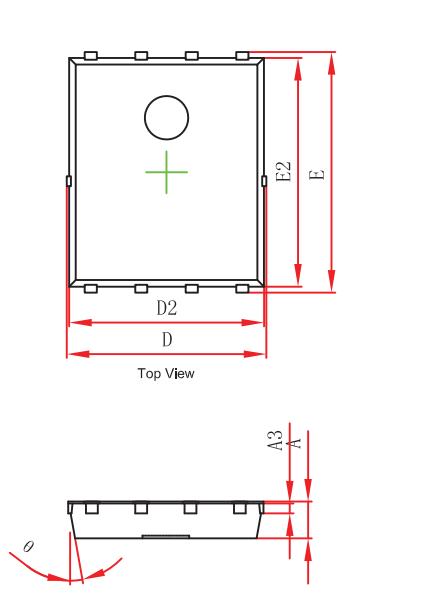


Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

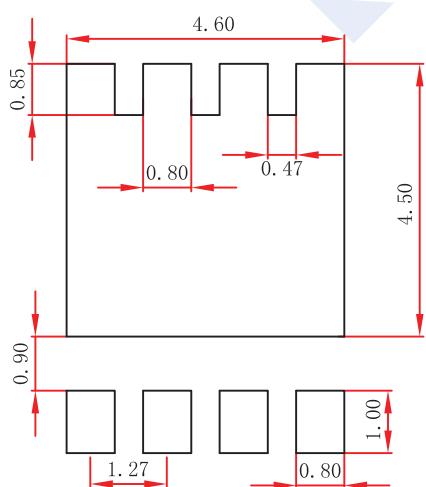


Diode Recovery Test Circuit & Waveforms



N-Channel MOSFET**AON6516 (KON6516)****■ DFN5x6-8(PDFNWB5x6-8L) Package Outline Dimensions**

Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.900	1.000	0.035	0.039
A3	0.254REF.		0.010REF.	
D	4.944	5.096	0.195	0.201
E	5.974	6.126	0.235	0.241
D1	3.910	4.110	0.154	0.162
E1	3.375	3.575	0.133	0.141
D2	4.824	4.976	0.190	0.196
E2	5.674	5.826	0.223	0.229
k	1.190	1.390	0.047	0.055
b	0.350	0.450	0.014	0.018
e	1.270TYP.		0.050TYP.	
L	0.559	0.711	0.022	0.028
L1	0.424	0.576	0.017	0.023
H	0.574	0.726	0.023	0.029
θ	10°	12°	10°	12°

■ DFN5x6-8(PDFNWB5x6-8L) Suggested Pad Layout**Note:**

1. Controlling dimension: in millimeters.
2. General tolerance: ± 0.05 mm.
3. The pad layout is for reference purposes only.